

Finite element analysis of cable shields to investigate the behavior of the transfer impedance with respect to fast transients

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General Overview

- Definition of transfer impedance
- Model description
- Simulation setup
- Results
- Outlook

Cable shields

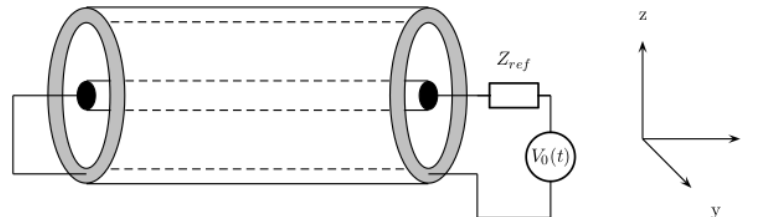
Definition of transfer impedance: [1]

- Defined as: Ratio between the transferred voltage per unit length on the internal surface of the shield and the longitudinal current on the external side of the shield
- Measured in Ohms per meter:

$$Z_t = \frac{\partial V_{tr}}{\partial x} \frac{1}{I_0} \quad \Omega/\text{m} \quad \text{where } x \text{ is the longitudinal space coordinate}$$

Used Setup:

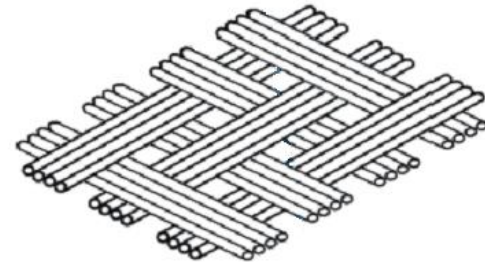
- The electromagnetic interference current (EMI current) is applied to the inner circuit formed by the inner conductor and the shield.
- This EMI current produces a differential transfer voltage on the outer side of the shield



Characterization of cable shields

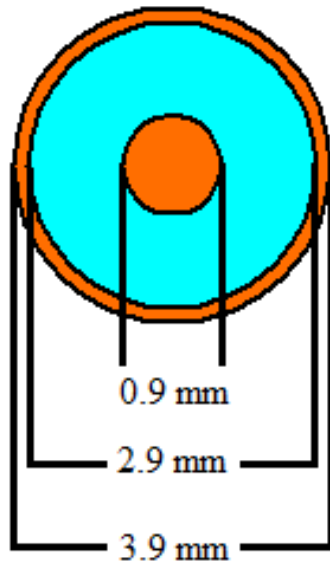
Characterization of transfer impedance of braided shields via terms of

- Inner radius of the shield
- Shield thickness
- Conductivity of the shield
- Weave angle of the shield
- Coverage factor
- Number of carriers
- Number of filaments
- Filament diameter



Cable model

Coaxial cable: RG58/CU, basic geometry



Geometry:

- Diameter of inner conductor: 0.90mm
- Inner diameter of shield: 2.90mm
- Outer diameter of shield: 3.50mm

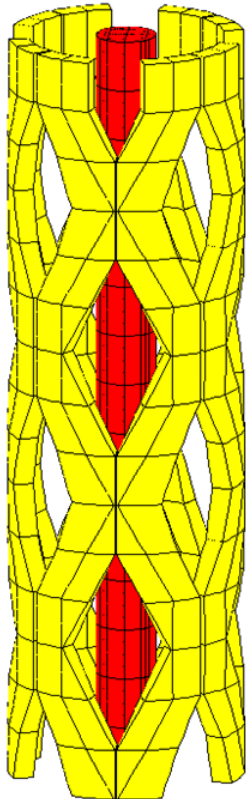
➤ *Shield thickness of 0.30mm*

Materials:

- Conductors: Copper, 56MS/m
- Dielectric: Polyethylene, $\epsilon_r = 2.4$

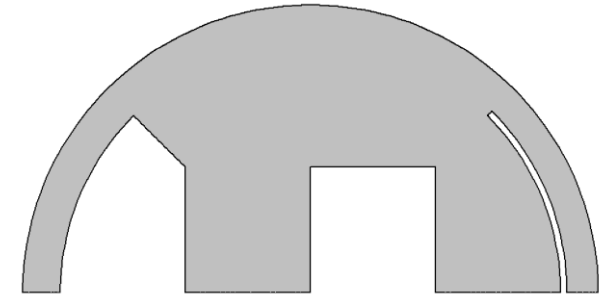
FEM- Model

ELEctromagnetic Field ANalysis Tool 3D



Model parameters

- Inner radius of the shield
- Shield thickness
- Conductivity of the shield
- Weave angle of the shield
- Coverage factor
- Number of carriers
- Number of filaments
- Filament diameter



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Skin effect and discretization issues

Exponential decrease of current density from its value at the surface J_S :

$$J = J_S e^{-\frac{z}{\delta}}$$

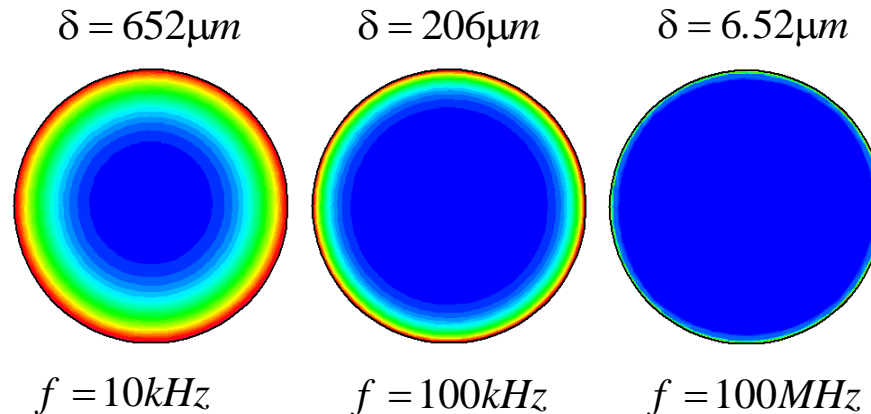
Where δ is the skin depth:

$$\delta = \sqrt{\frac{2 \cdot \rho}{\omega \mu}}$$

ρ ... resistivity of the conductor

ω ... angular frequency

μ ... permeability $\mu = \mu_0 \cdot \mu_r$



Simulation

- For the numerical analysis, the $\mathbf{A}, V\text{-}\mathbf{A}$ - formulation is used [2]
- A magnetic vector potential \mathbf{A} and an electric scalar potential V represented by a modified scalar potential v are introduced
- The magnetic vector potential \mathbf{A} is used in the non-conducting region Ω_i and in the conducting region Ω_c
- The scalar potential v is used in the conducting region Ω_c

$$\mathbf{B} = \nabla \times \mathbf{A} \text{ in } \Omega_c \text{ and } \Omega_i$$

$$\mathbf{E} = -\frac{\partial \mathbf{A}}{\partial t} - \nabla V = -\frac{\partial \mathbf{A}}{\partial t} - \nabla \frac{\partial v}{\partial t} \text{ in } \Omega_c$$

Simulation (2)

For an eddy current problem with current excitation, the boundary conditions are

$\Gamma_{E1}, \Gamma_{E2} \dots$ surfaces of the electrodes

$$v_0 = 0 \text{ on } \Gamma_{E1} \text{ and } v_0 = v_x \text{ on } \Gamma_{E2}$$

$v_x \dots$ voltage between these two electrodes

With a given current I_0 the following relationship has to be satisfied additionally:

$$\int_{\Gamma_{E2}} \sigma \left(\frac{\partial \mathbf{A}}{\partial t} + \nabla \frac{\partial v}{\partial t} \right) \cdot \mathbf{n} d\Gamma = I_0$$

Applying Galerkin techniques leads to a system of first order differential equations

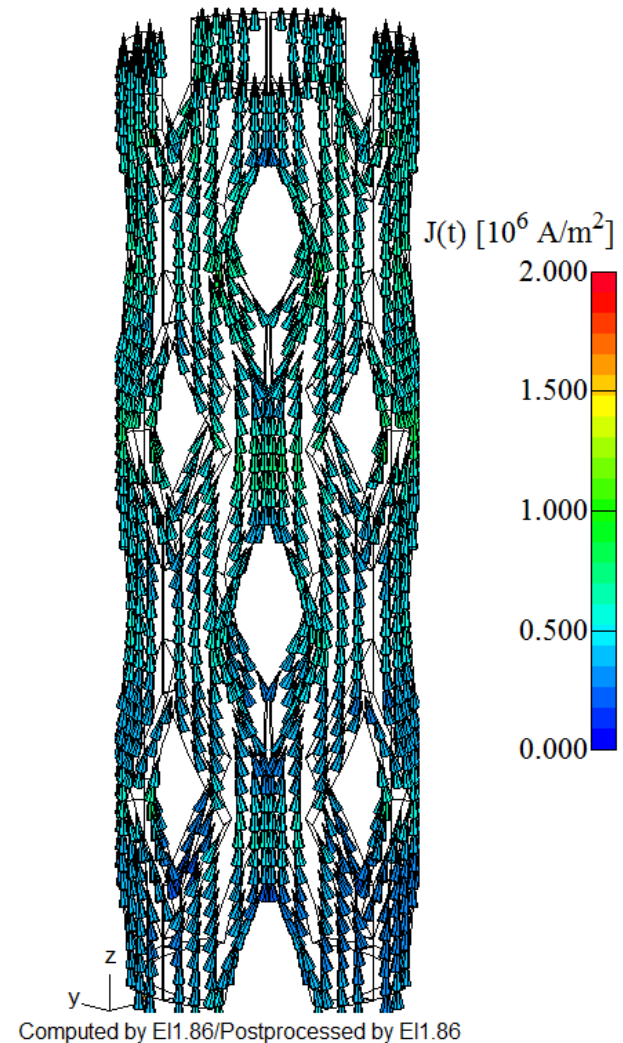
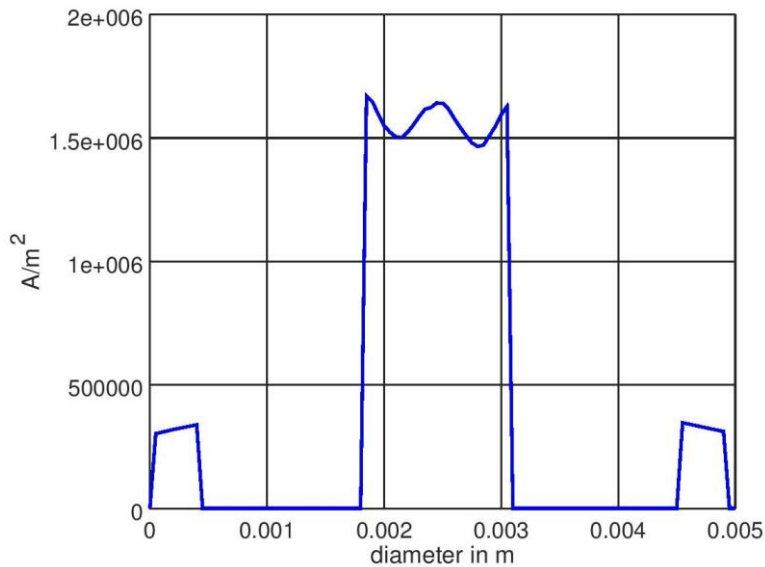
$$[A]\{a\} + [B]\{\dot{a}\} = \{b\}$$

This is solved by time-stepping applying the backward Euler scheme [3] resulting in a system of algebraic equations

$$[A]\{a_k\} + \frac{1}{\Delta t_k} [B]\{a_k\} = \frac{1}{\Delta t_k} [B]\{a_{k-1}\} + \{b_k\}$$

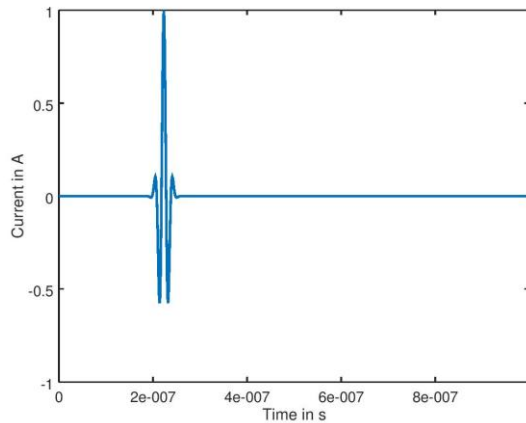
Test results at 100kHz

Line diagram of current density evaluated over the cable diameter

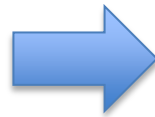
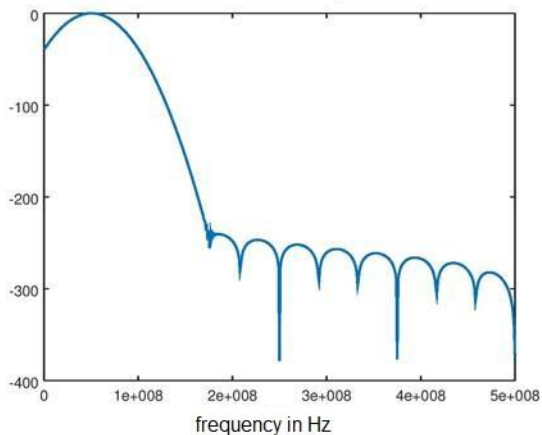


Broadband investigation

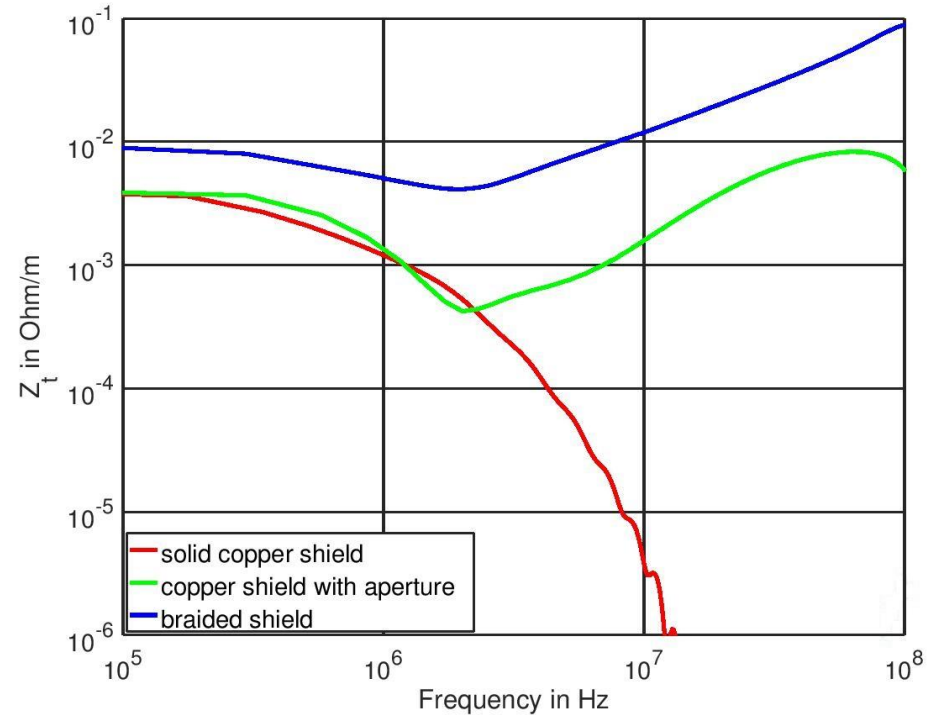
As input function
a gaussian pulse is applied



Baseband spectrum of $i(t)$ in dB



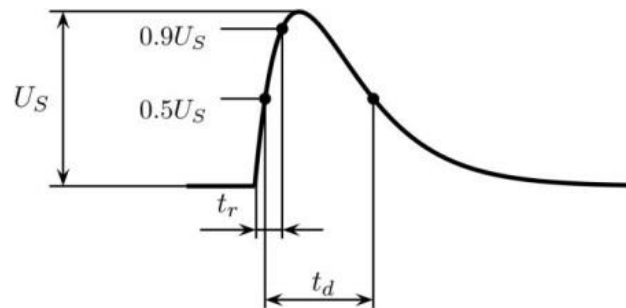
Transfer impedance vs frequency



Solid shield, copper shield with aperture and
braided shield

Transient simulation

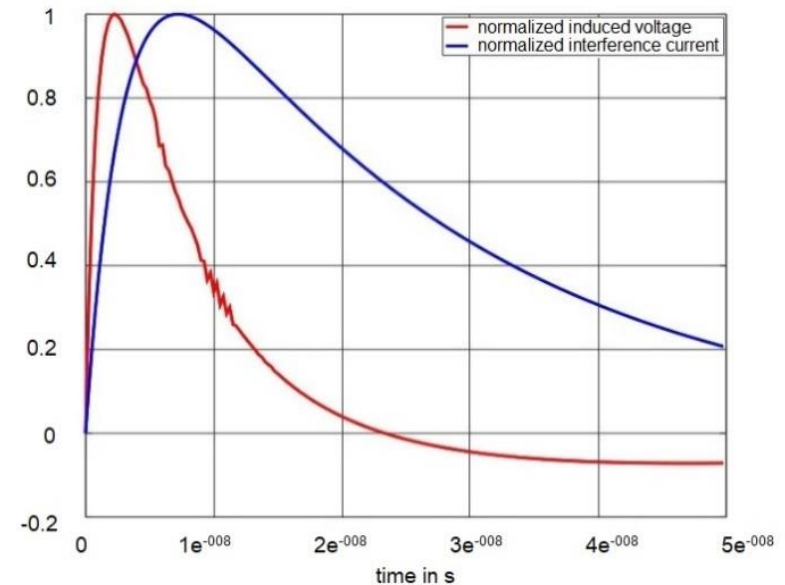
As input function the standardized EFT/BURST pulse was applied via a 50 Ω resistance (IEC 61000-4-4:2012)



Set Voltage: U_S Rise-time: t_r Pulse Width: t_d
 1000 V (5 \pm 1.5)ns (50 \pm 15)ns

The testing signal is modelled as a double exponential pulse [4]:

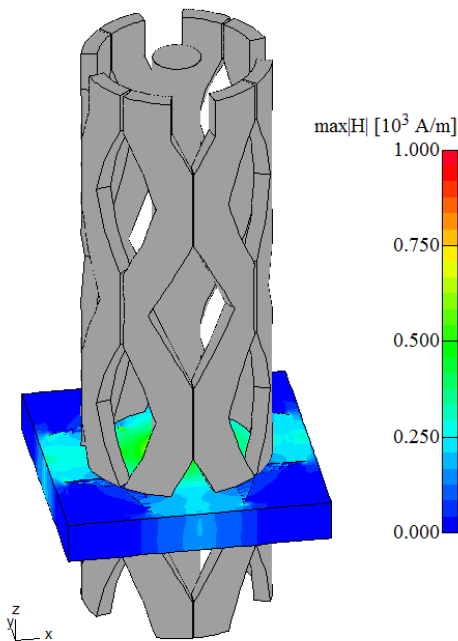
$$V_0(t) = V_S \cdot k \left(e^{-\alpha t} - e^{-\beta t} \right)$$



applied current vs normalized induced voltage

Outlook

- Refining the geometry
- Parameterized model for sensitivity analysis
- Extraction of manageable model for further simulation (SPICE)



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Cable deformities such as pinched cables and their influence on signal integrity and crosstalk

- Impedance mismatch, since the characteristic impedance is geometry dependent
- Apertures in the shield create an additional path for the electromagnetic coupling between the inside and the outside of the shield

References

- (1) S.A. Schelkunoff, “The Electromagnetic Theory of Coaxial Transmission Lines and Cylindrical Shields”,
The Bell System Technical Journal, Volume 13, Issue 4, Oct. 1934
- (2) O. Bíró, K. Preis, “On the use of the magnetic vector potential in the finite-element analysis of three-dimensional eddy currents”,
IEEE Transactions on Magnetics, Vol. 25, No. 4, July 1989
- (3) B. Weiss, O. Bíró, ”On the Convergence of Transient Eddy-Current Problems”,
IEEE Transactions on Magnetics, Vol. 40, No. 2, March 2004
- (4) M. Magdowski, R. Vick, “Estimation of the Mathematical Parameters of Double-Exponential Pulses Using the Nelder-Mead Algorithm”, *IEEE Transactions on Electromagnetic Compatibility*, pp1060-1062, Nov. 2010

Thank you for your attention

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